

**Search Notes**

Application/Control No.

10/571,195

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	6/27/2008	PL
Inventor name search updated EAST/PALM	6/27/2008	PL
STN updated (fil reg/Indexed BIOSCIENCE & napralert - approx. 76 databases)	6/27/2008	PL